



Jake P. Cohen

Director

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Background

Jake Cohen is a manager specializing in intellectual property litigation at Elysium Digital.

Specializing in patent and software analysis, Jake has analyzed multiple products at Elysium Digital, spanning a variety of industries. In addition to analyzing source code, Jake has assisted at depositions by developing strategic follow-up questions in real time.

Jake has a B.S. with high honors in physics and a B.A. in mathematics from Brandeis University. Jake also holds certifications in Digital Forensics and Incident Response from GIAC (Global Information Assurance Certification).

Prior to joining Elysium Digital, Jake worked in a research lab at Brandeis and briefly at the Raman Research Institute in Bangalore analyzing and processing data associated with radio galaxies.

Professional Experience

- Elysium Digital, LLC, a subsidiary of Aon Corporation, Director, 2023 – Present
- Elysium Digital, LLC, a subsidiary of Aon Corporation, Manager, 2020 – 2023
- Elysium Digital, LLC, a subsidiary of Aon Corporation, Senior Consultant, 2019 – 2020
- Stroz Friedberg, LLC, an Aon company, Senior Consultant, 2018 – 2019
- Stroz Friedberg, LLC, an Aon company, Consultant, 2016 – 2018
- Stroz Friedberg, LLC, an Aon company, Cyber Associate, 2015 – 2016

Education

- B.S., high honors, Physics, Brandeis University, 2015
- B.A., Mathematics, Brandeis University, 2015

Certifications

- GIAC Certified Incident Handler (GCIH), Global Information Assurance Certification, 2016

Training

- CopyrightX, Harvard Law School, 2018
- SEC 504: Hacker Tools, Techniques, Exploits and Incident Handling, The SANS Institute, 2016
- FOR 408: Windows Forensic Analysis, The SANS Institute, 2015

Publications

- "The Abundance of X-shaped Radio Sources. I. VLA Survey of 52 Sources with Off-axis Distortions." David H. Roberts, Jake P. Cohen, Jing Lu, Lakshmi Saripalli, Ravi Subrahmanyam. *The Astrophysical Journal Supplement Series* 220.1 (2015): 7